

Automate yield analysis across 100% of your data — and eliminate weeks of manual root cause diagnosis.



Complete 70–90% of analysis with minimal expertise and just a few clicks

AI-Powered Guided Analytics Platform

Exensio® Guided Analytics (GA) is an **AI-driven** analytics layer across the Exensio platform that automates daily mining of 100% of manufacturing and test data, enabling **AI-driven prioritization** and **guided drill-down** to resolve **product yield limiters** across your supply chain within seconds.

Problem with Status Quo

Teams manually evaluate just 3–5% of available data monthly, spending weeks aligning data types and missing yield excursions.

Guided Analytics systematically analyzes **100% of aligned data** every day.

Solution Highlights



Prioritize **yield limiters** across all products

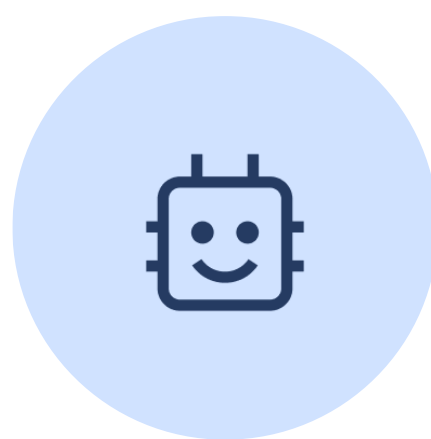


Diagnose **root causes** with automated **AI/ML** analysis



Navigate **guided flows** from dashboard to drill-down

Components



AI/ML Root Cause Analysis

Links yield excursions to **PCM/WAT** and **test cell equipment** through automated ML diagnosis.



Automated Yield Dashboard

Ranks **yield** and **bin trends** by **AI-scored impact**, surfacing top limiters for triage.



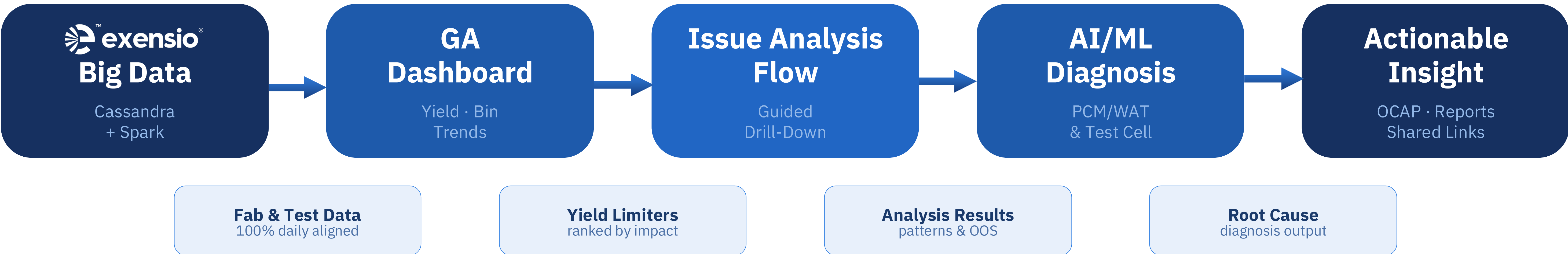
Structured Analysis Flows

Guides analysts from **summary** to **drill-down** via three structured flow modes.



Test Operations Module

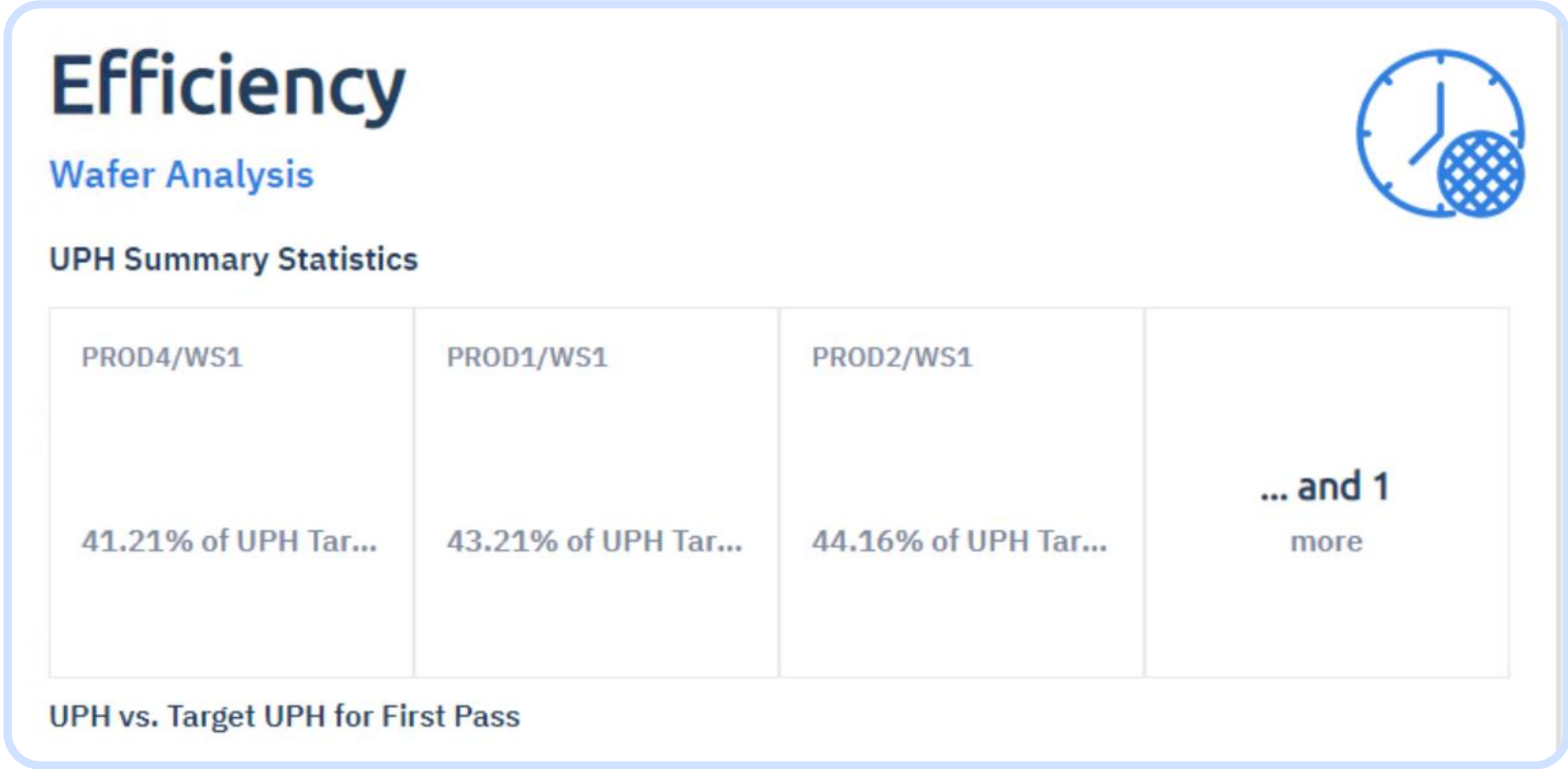
Extends to **wafer sort** and **final test**, tracking **UPH** trends and tester health.



Use Cases

Test Cell Efficiency Analysis

A test operations team noticed **throughput variation** across tester types on a key product. Using the GA, they identified a subset of testers with degraded **UPH** and correlated the pattern to a **software configuration mismatch** — enabling targeted maintenance without manual data extraction.



Challenge

Daily yield review required **manual** cross-referencing of multiple data sources, delaying root cause identification by weeks.



Result

GA **automated** daily alignment of Bin, PCM/WAT, and wafer map data — reducing root cause time from weeks to hours.



Challenge

Identifying low-performing testers required exporting and **manually** analyzing UPH and bin data across dozens of test cells.

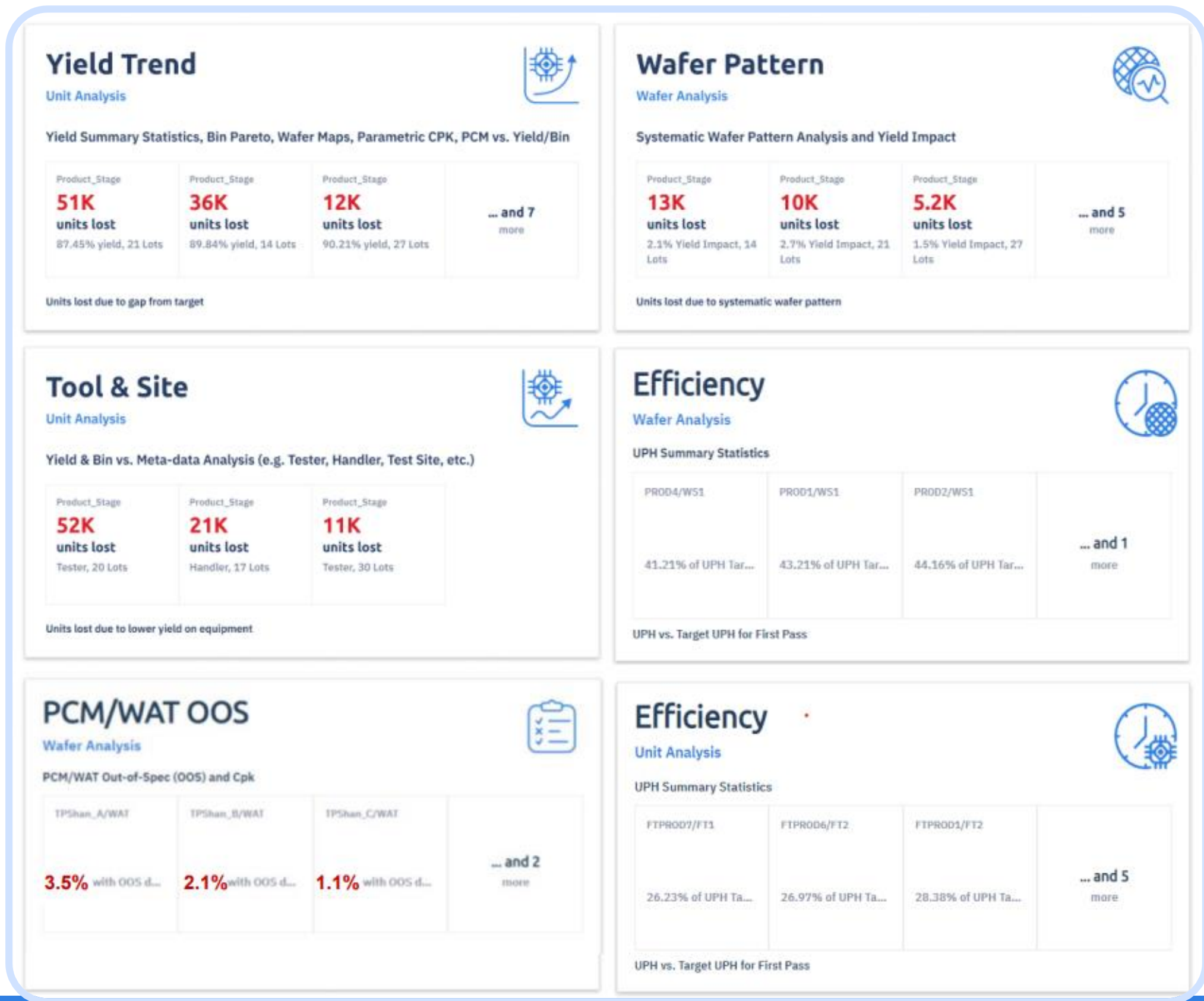


Result

GA-TO surfaced tester UPH outliers and bin pattern deviations, enabling targeted maintenance within one shift.

Yield Excursion Auto-Triage

A yield engineer at a logic fab was alerted to **Bin 6 yield degradation**. Using the GA Yield Trend guided flow, the engineer identified a **PCM/WAT out-of-spec correlation** in minutes - without manual database queries - and shared the finding with the process team via a shareable link.



90%

analysis automated

40×

faster summarization

100%

of data mined daily

results based on typical Extensio® customers

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